

University of Padova
Department of Information Engineering

Current and temperature dependence of electroluminescence in InGaN-based LEDs with multi-wavelength emission

Summer School of Information Engineering
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Outline

- Introduction:
 - loss mechanisms occurring in InGaN-based LEDs;
 - problems related to MQW structures;
- Experimental details;
- Electroluminescence analysis:
 - current-dependent effects;
 - temperature-dependent effects.
- Conclusion.



Introduction

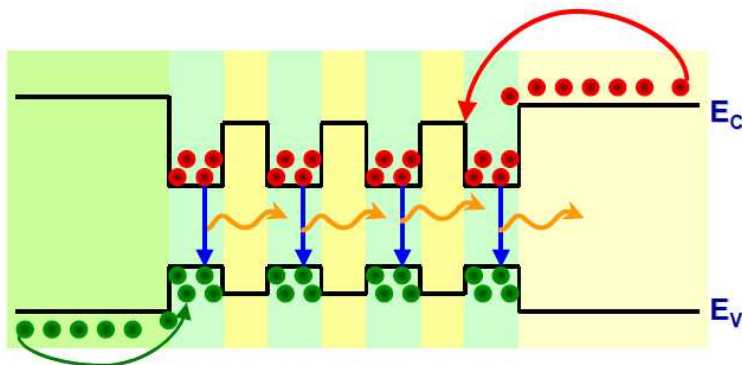
InGaN-based Light-Emitting Diodes are required in most applications:

- street and indoor lighting;
- traffic lights;
- automotive.



Loss mechanisms occurring at high current densities:

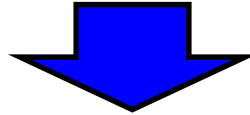
- solution → distribution of carriers on a large number of wells




Multiquantum well (MQW) structures

Introduction

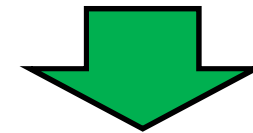
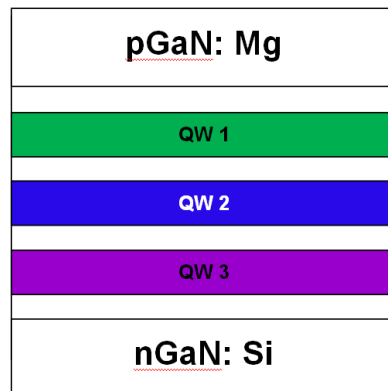
- **Problem**: in InGaN MQW LEDs few wells contribute to the emission



usually due to the low mobility and density of holes

- Information about carrier distribution can be obtained from multicolor LEDs  each well emits its own characteristic color

- **Aim of this work**: to analyze the carrier distribution in InGaN-based LEDs at different temperature and current levels



analysis carried out on triple-quantum well
InGaN-based LEDs

Experimental details

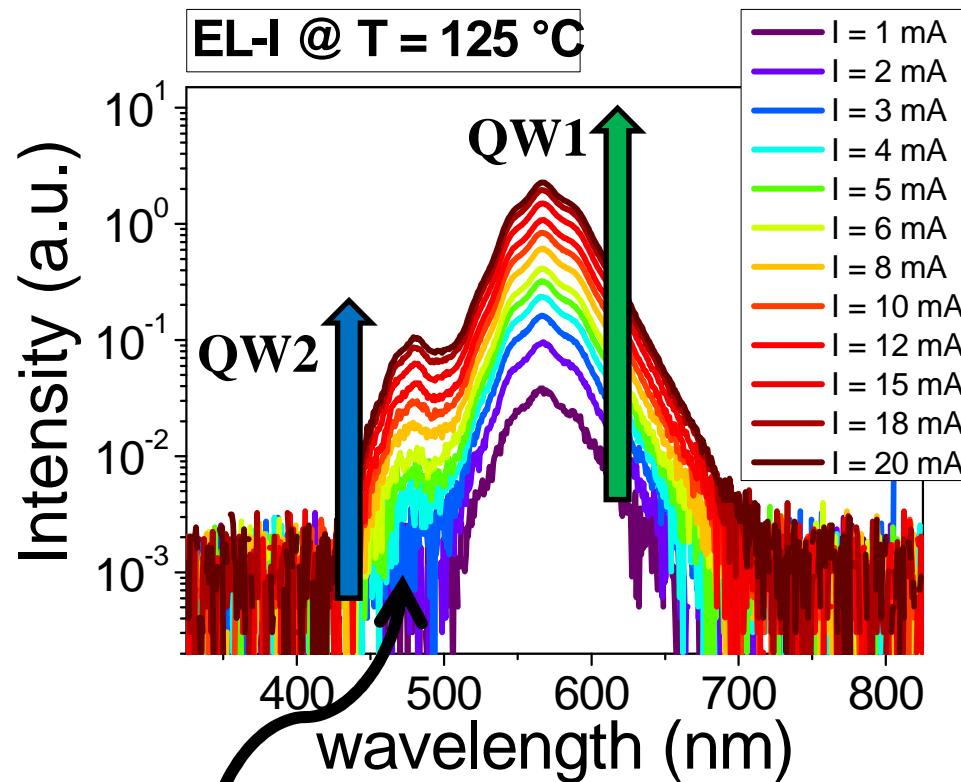
pGaN: Mg
QW 1
QW 2
QW 3
nGaN: Si

	Indium content (%)	wavelength emission (nm)
QW1	25	560
QW2	15	460
QW3	5	400

- Sapphire substrate (density dislocations $\sim 5 \times 10^9 \text{ cm}^{-2}$)
- n-GaN layer Si-doped
- p-GaN layer Mg-doped grown at 925 °C
- Active region: three quantum wells (2-3 nm) with different indium content in each well

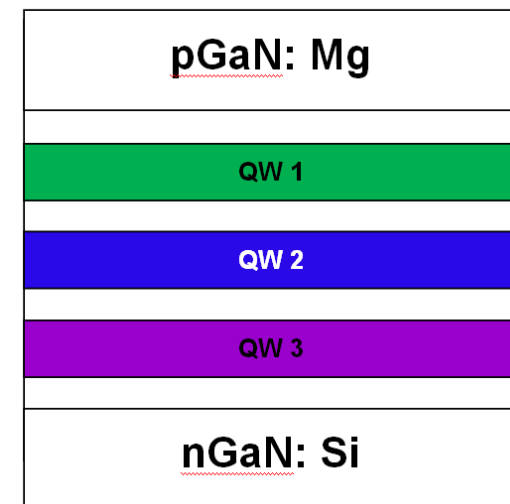
Characterization: EL measurements at different temperature and current levels.

EL analysis: current-dependent effects



Two current dependent-effects:

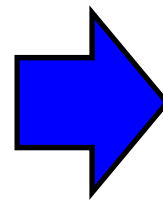
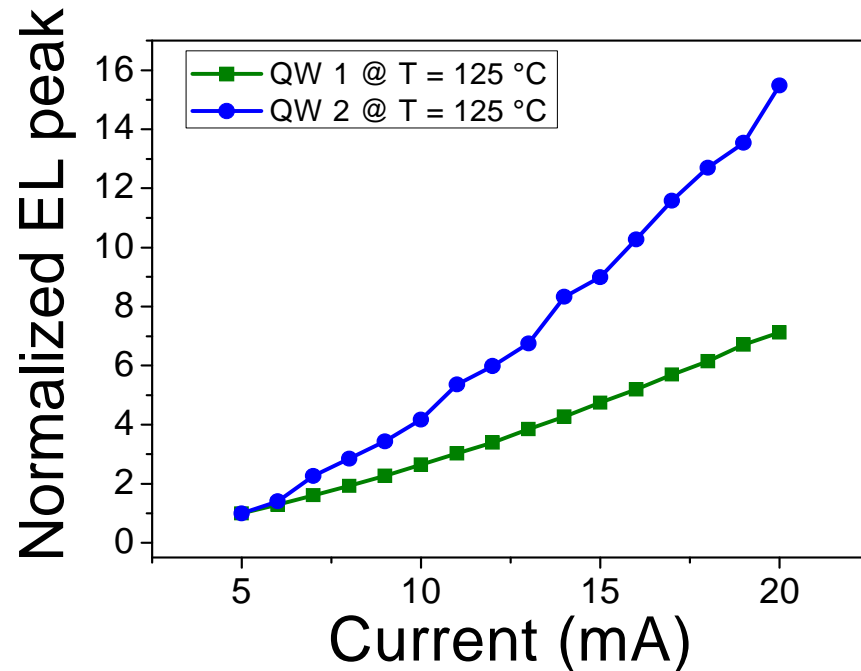
1. increase in the EL intensity from both QW1 (560 nm) and QW2 (460nm) with increasing current;
2. no emission from QW3 (400 nm).



At low current levels no emission from QW2

efficiency limited by poor hole injection

EL analysis: current-dependent effects



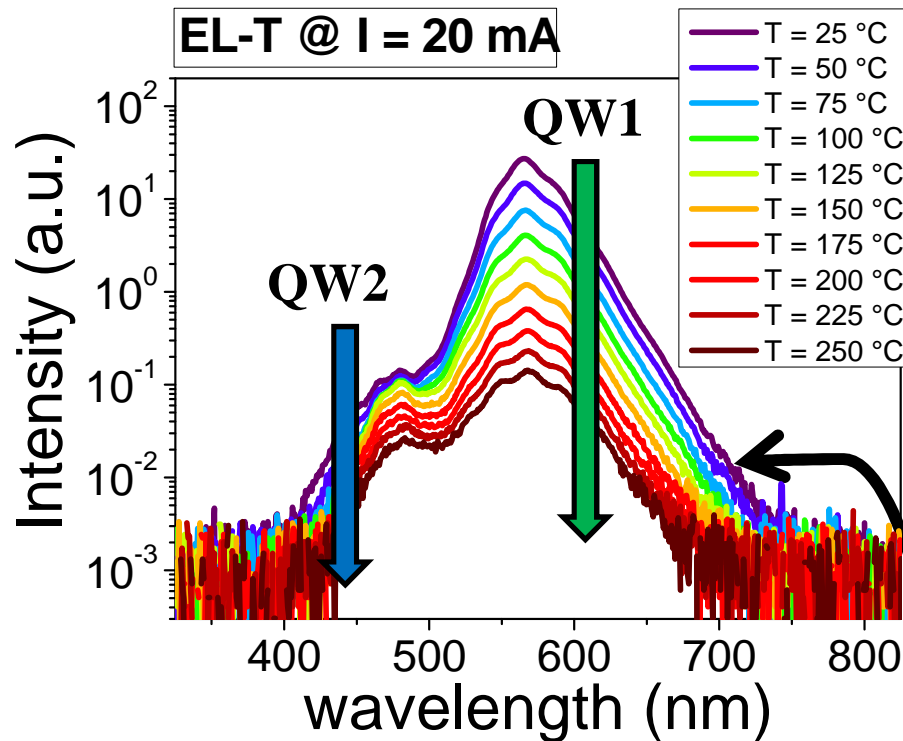
Increase of emission from QW2 particularly prominent at high current levels

At high current levels more carriers injected in the active region:



increase in the radiative recombination rate

EL analysis: temperature-dependent effects

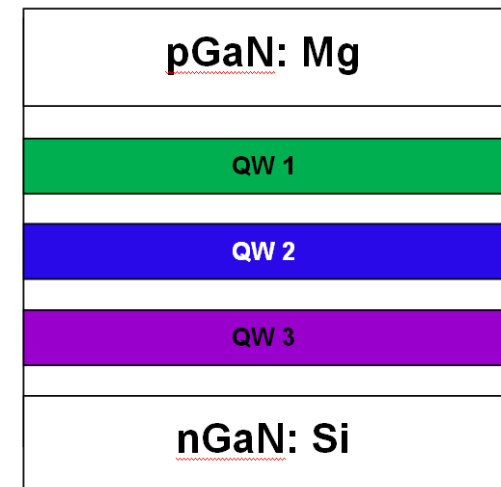


Two temperature dependent-effects:

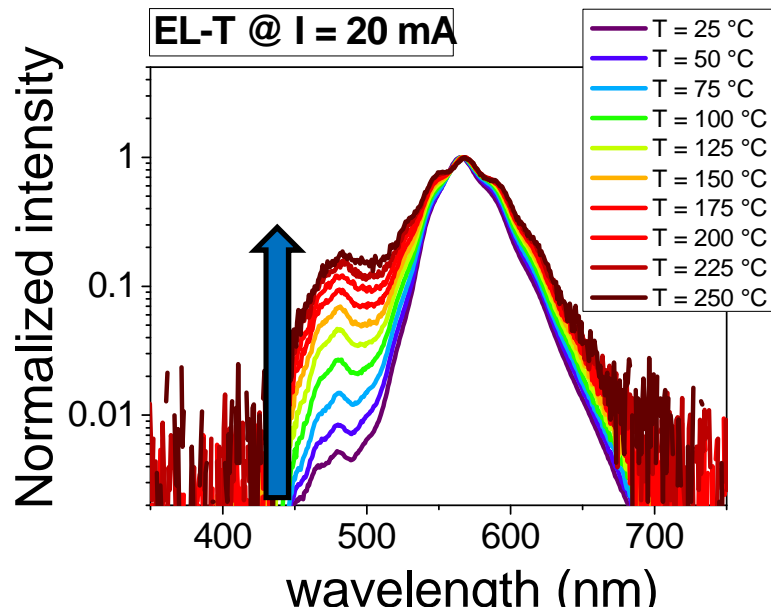
1. decrease in the EL intensity from both QW1 (560 nm) and QW2 (460nm) with the increasing of temperature;
2. no emission from QW3 (400 nm).

Decrease in the emission with increasing temperature

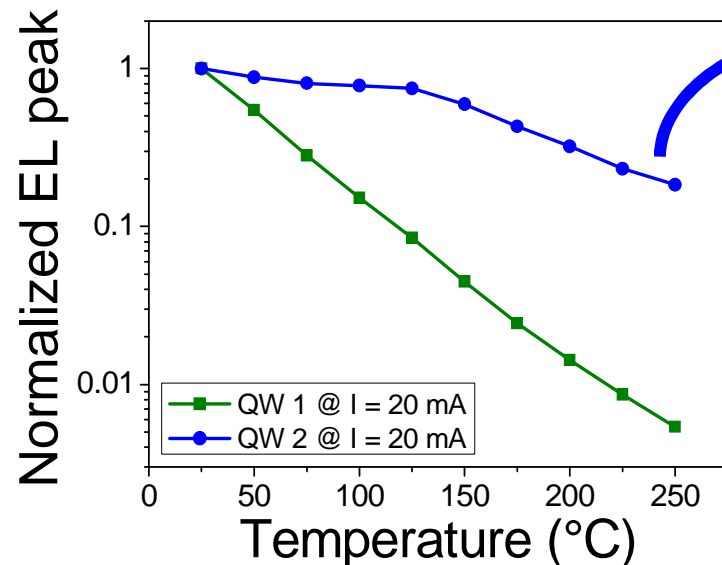
 increase in nonradiative recombination.



EL analysis: temperature-dependent effects



Decrease of emission from QW2 (460 nm) less prominent with respect to QW1 (560 nm)




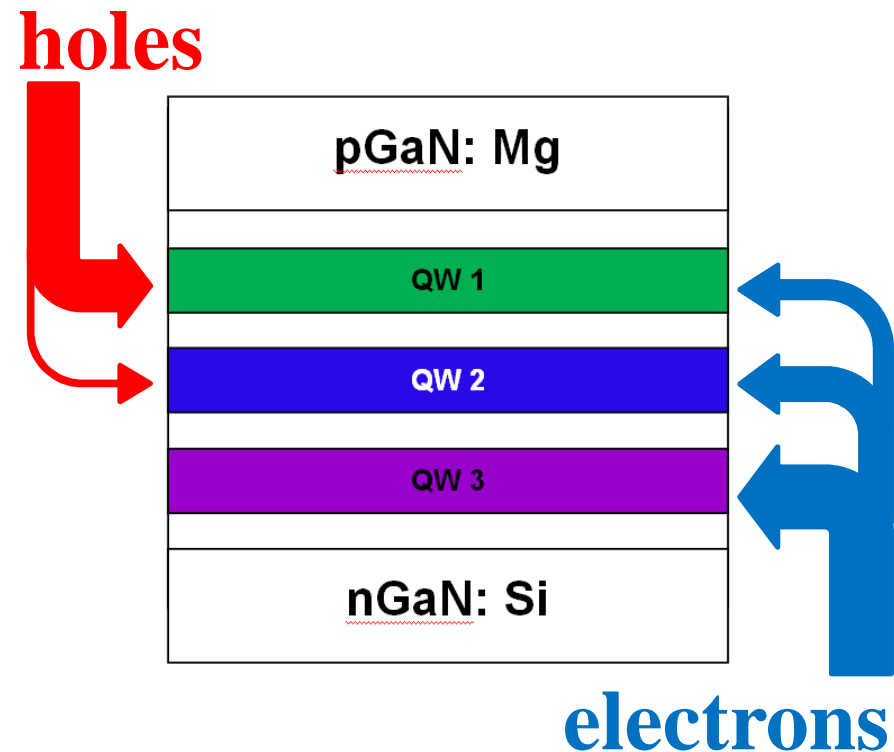
At high temperature operation increased hole injection

EL analysis: temperature and current-dependent effects

- The previous results suggest a poor hole injection

- At high temperature levels:

1. holes with more thermal energy  increased probability of escaping QW1 and reaching QW2;
2. stronger activation of the acceptor dopant (Mg).



- At high current levels: more holes can reach the second quantum well

Conclusions

- Analysis of carrier distribution in triple-quantum well InGaN-based LEDs has shown that:
 1. MQW InGaN-LEDs efficiency is limited by poor hole injection;
 2. more holes can reach the second quantum well away from the *p*-type layer at high temperature and current levels.
- Future works:
 1. photoluminescence and cathodoluminescence measurements;
 2. analysis on similar structures (different position and thickness of wells).

Thanks for your attention

